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12 April 2023

PCN-01543

Digi-Key Corporation
701 Brooks Ave South
Thief River Falls, Minnesota 56701

Subject: Additional testing and packaging site.

Dear Valued Customer,

MACOM Technology Solutions has a goal of providing redundant manufacturing capability for increased surge capacity as well as an uninterrupted supply chain. In alignment with this goal, we are pleased to announce an additional testing and packaging site for the parts listed in the next pages.

In addition to our current testing and packaging sites, we planned to test and package these parts at our long-standing Contract Manufacturer, Year 2000, Ho Chi Minh City, Vietnam. Year 2000 is a valued, high-quality manufacturing partner for many MACOM products.

In accordance with MACOM Technology Solutions' customer notification policy, you are receiving this notice because you have purchased one or more of the products listed in the previous two-year period.

Please contact your local sales representative if you have any specific questions.

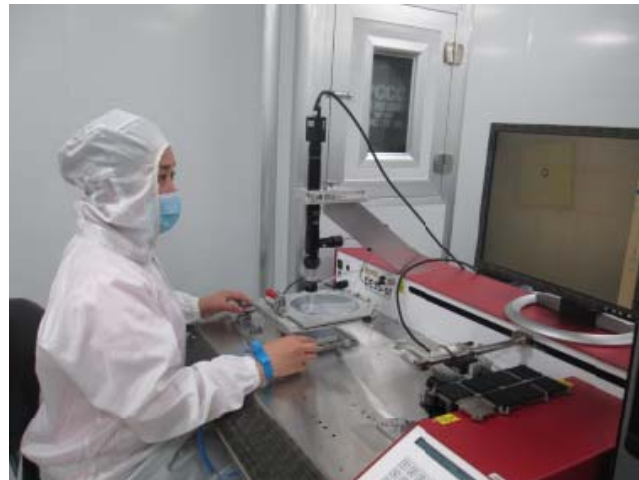
Sincerely

Tom Galluccio
Director, Product Marketing
thomas.galluccio@macom.com

Appendix I
Affected part numbers

Part Number	Part type
M5X4859	Diode
M5X6043	Diode
M5X4350	Diode
M2X3310	Diode
M5X5472	Diode
M5X4952	Diode
MPN7320-C01	Diode
M5X5171	Diode
MX51944-11	Diode
M5X3345	Diode
M5X6100	Diode
M5X5478	Diode
MPN7640-C12	Diode
MCC100-20D	Capacitor
910R7J	Capacitor
9035RK-SP	Capacitor
MCC100-15B	Capacitor
M3X2256	Capacitor
M3X2442	Capacitor
MCC100-5C	Capacitor

Appendix II
The new testing and assembly facility



Appendix III

Qualification process capability data

Two representative part numbers(MX51267-11 and MC2S022025-025) are tested and qualified in Year 2000 as below, and the rest parts in the pcn can be qualified by similarity to the representative parts as they have the same production process.

1. Diode.

MX51267-11

Test conditions: IR1max=10uA, under -1100V.

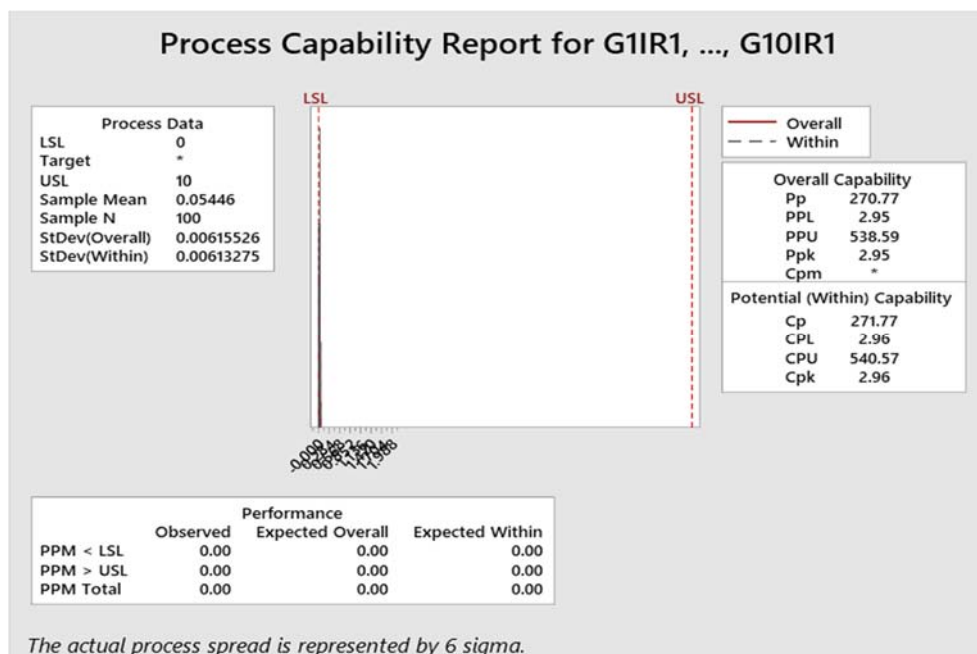
IR2max=0.05uA, under -1000V.

Cj1max=0.25pF, under -28V.

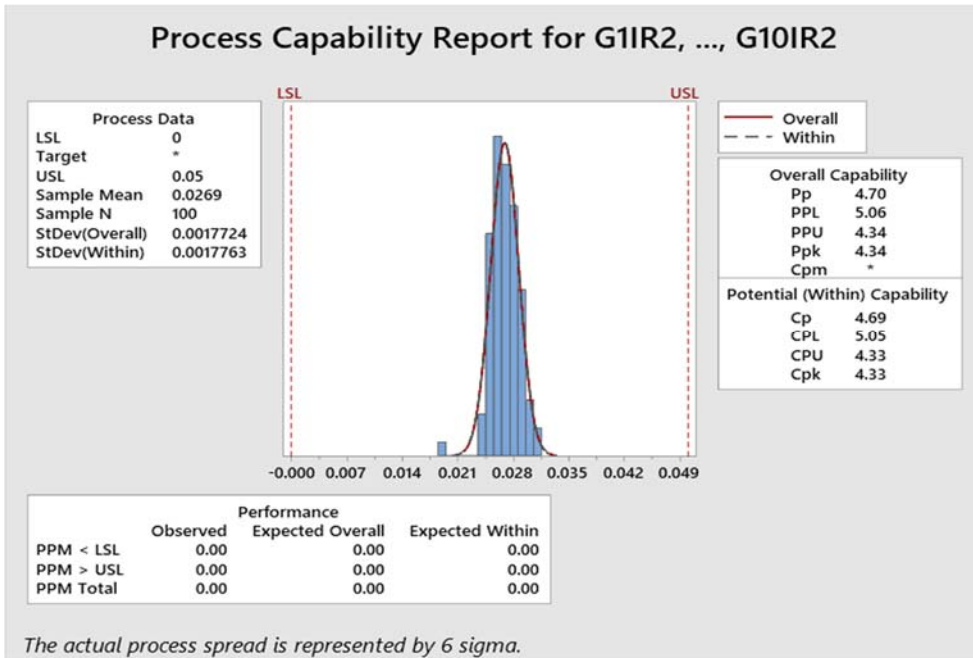
VF1max=1.25V, under 100mA.

Sample size=100,10 sub-groups.

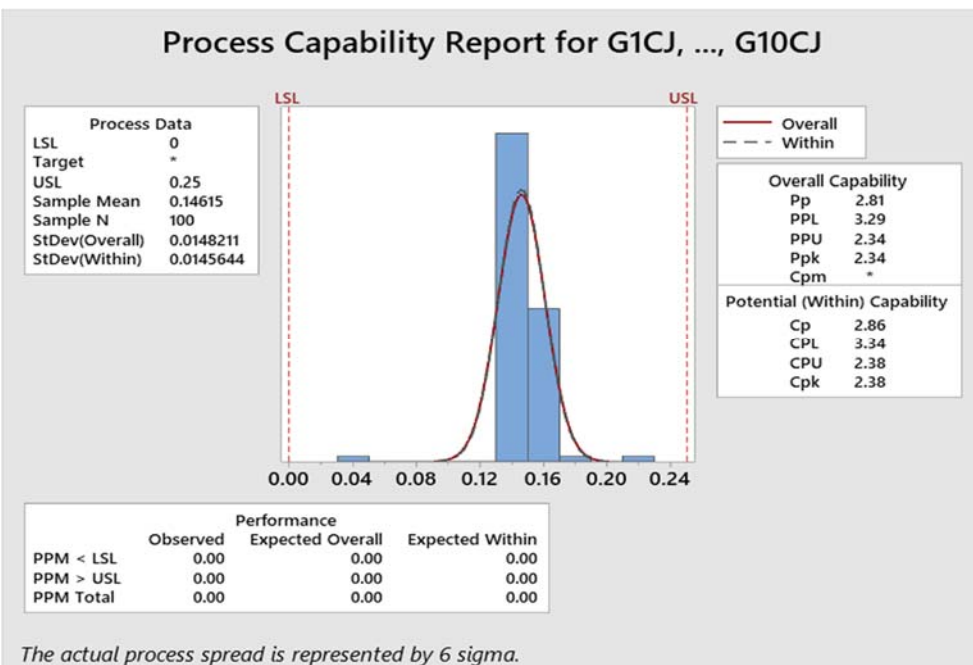
IR1:



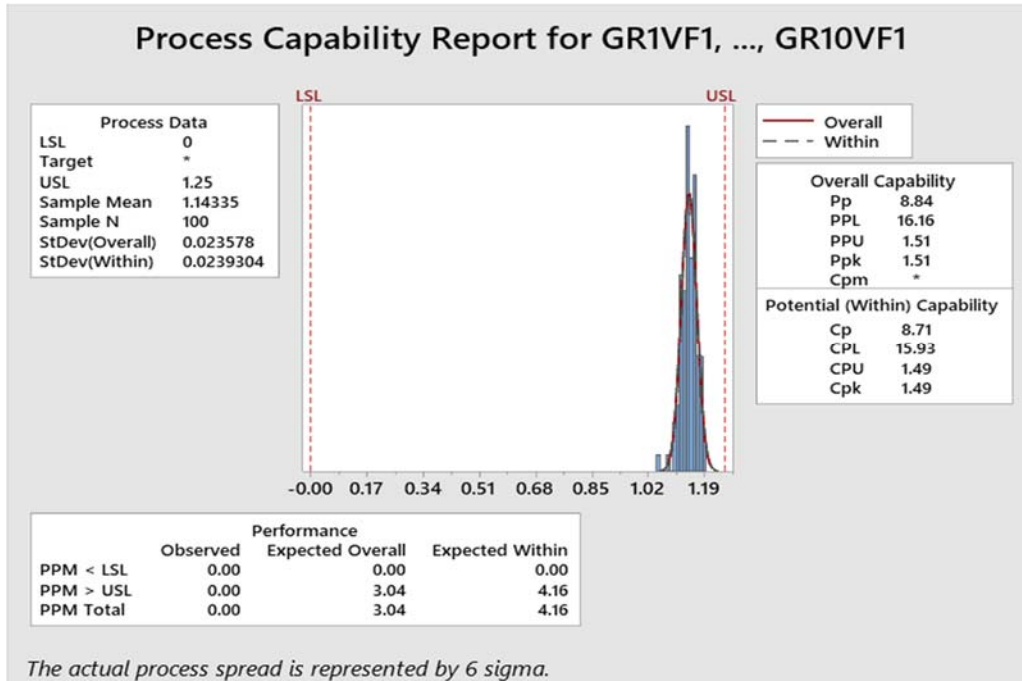
IR2:



Cj1:



VF1:



2. Capacitor.

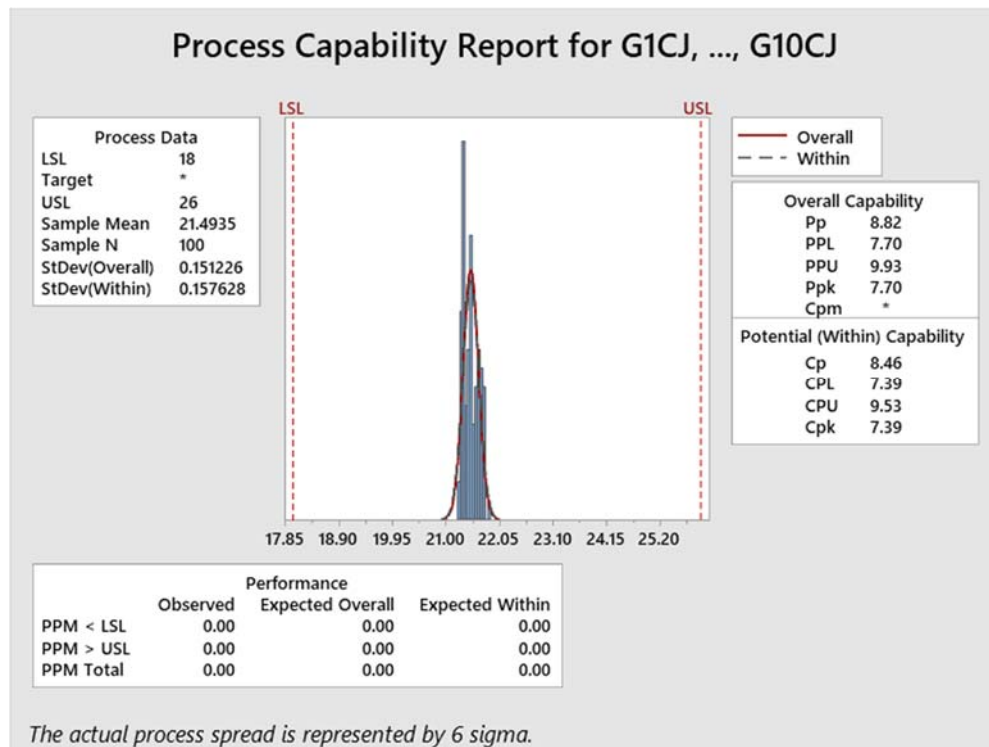
MC2S022025-025

Test conditions: Cj1min=18pF, Cj1max=26pF, under 0V.

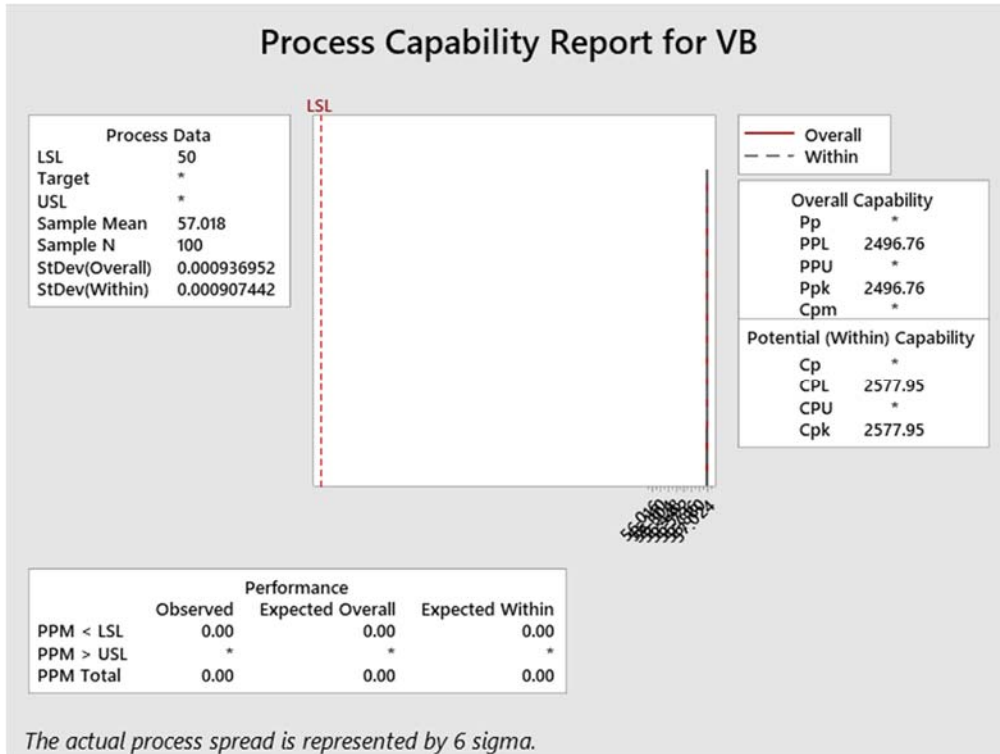
VBmin=50V, under -10uA.

Sample size=100,10 sub-groups.

CJ1:



VB:

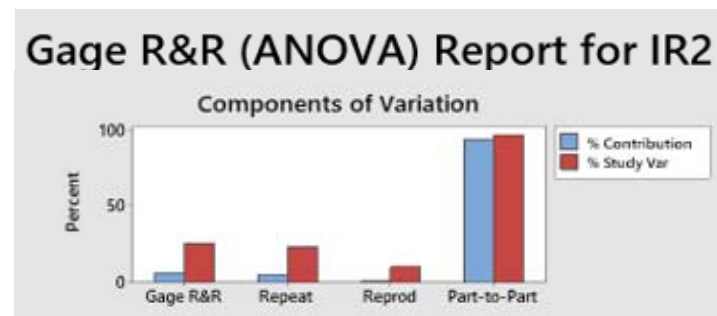
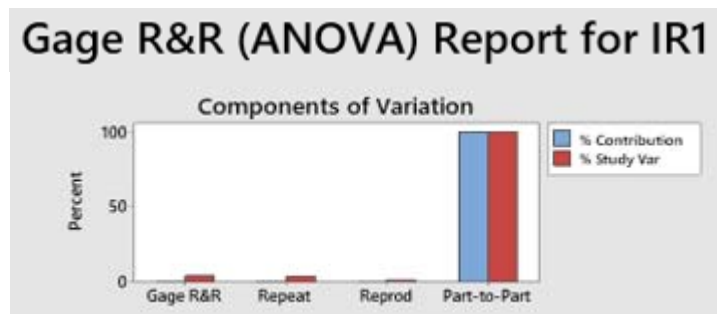


Appendix IV
Qualification Gage R&R testing data

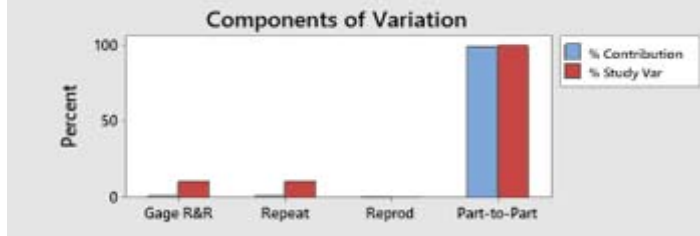
1. Diode test parameters

GR&R summary:

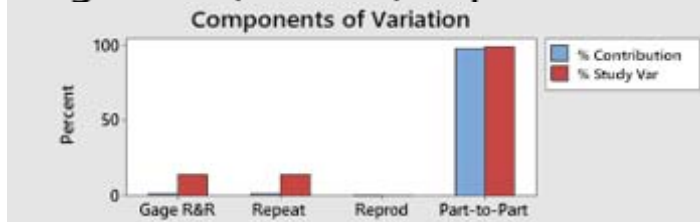
Specification:-			
a) GR&R Contribution % $\leq 10\%$			
b) GR&R Variation % $\leq 30\%$			
Parameter	GR&R Contribution % GR&R	GR&R Variation% GR&R	Result
IR1	0.21	4.57	PASS
IR2	6.62	25.72	PASS
Cj1	1.13	10.65	PASS
VF1	2.13	14.6	PASS



Gage R&R (ANOVA) Report for Cj1



Gage R&R (ANOVA) Report for VF1



2. Capacitor test parameters

GR&R summary:

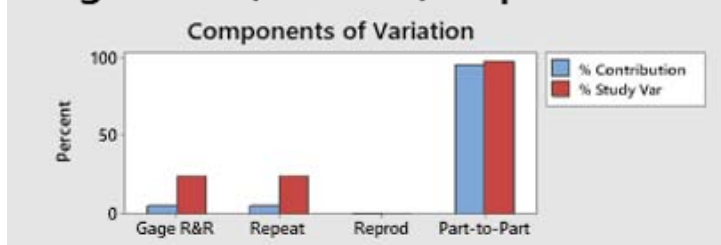
Specification:-

a) GR&R Contribution % $\leq 10\%$

b) GR&R Variation % $\leq 30\%$

Parameter	GR&R Contribution % GR&R	GR&R Variation % GR&R	Result
VB	5.69	23.85	PASS
Cj1	0	0.67	PASS

Gage R&R (ANOVA) Report for Vb



Gage R&R (ANOVA) Report for Cj1

